Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
09/989,662	TAKANO ET AL.
Examiner	Art Unit
TUAN A. PHAM	2643

	SEARCHED					
Class	Subclass	Date	Examiner			
455	436	5/1/2005	РНАМ			
	442					
	439					
	443					
	437					
	67.11					
	69					
	522					
	525	5/2/2005	PHAM			

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
		-			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
		DATE	EXMR
Consulted With:			
Nguyen Vo		5/2/2005	РНАМ
Binh Tieu			
		<b></b>	
		<del> </del>	_
		7:	